

Notice of References Cited		Application/Control No. 10/518,770	Applicant(s)/Patent Under Reexamination USHIDA ET AL.	
		Examiner HENOK G. HEYI	Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,827,593 A	10-1998	Maruyama et al.	428/64.1
*	B	US-5,851,620 A	12-1998	Nakajima et al.	428/64.1
*	C	US-6,068,906 A	05-2000	Sasa et al.	428/64.2
*	D	US-2002/0085482 A1	07-2002	Kikuchi et al.	369/275.1
*	E	US-2003/0161255 A1	08-2003	Kikuchi et al.	369/280
*	F	US-2003/0199601 A1	10-2003	Chang et al.	522/71
*	G	US-6,743,527 B2	06-2004	Hisada et al.	428/846.9
*	H	US-2004/0148622 A1	07-2004	Kurokawa et al.	720/718
*	I	US-2005/0007945 A1	01-2005	Usami et al.	369/282
*	J	US-6,889,381 B2	05-2005	Kikuchi et al.	720/718
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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